

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
242947US2S DIVSERIAL NO.
10/669,525

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Hideo ANDO, et al.FILING DATE
September 25, 2003GROUP
~~2055~~ 2616

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>W</i>	AA	6,212,330-A	04/2001	YAMAMOTO et al.	—	—	
<i>W</i>	AB	5,991,502	11/1999	KAWAKAMI et al.	—	—	
<i>W</i>	AC	6,181,870	01/2001	OKADA et al.	—	—	
<i>W</i>	AD	6,253,026	06/2001	SAEKI et al.	—	—	
<i>W</i>	AE	6,263,155	07/2001	SAEKI et al.	—	—	
<i>W</i>	AF	6,347,187	02/2002	SAEKI et al.	—	—	
<i>W</i>	AG	6,167,189-A	12/2000	TAIRA et al.	—	—	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>W</i>	AH	JP 11-16824	01/22/99	JAPAN		X
<i>W</i>	AI	JP 2000-13728	01/14/00	JAPAN		X
<i>W</i>	AJ	JP 5-74053	03/26/93	JAPAN		X
<i>W</i>	AK	7-211048	08/11/95	JAPAN		X
<i>W</i>	AL	JP 8-263969	10/11/96	JAPAN		X
<i>W</i>	AM	JP 10-289533	10/27/98	JAPAN		X
<i>W</i>	AN	JP 5-346879	12/27/93	JAPAN		X
<i>W</i>	AO	JP 9-91878	04/04/97	JAPAN		X
<i>W</i>	AP	JP 9-23404	01/21/97	JAPAN		X
<i>W</i>	AQ	JP 9-259572	10/03/97	JAPAN		X
<i>W</i>	AR	JP 5-81787	04/02/93	JAPAN	X	
<i>W</i>	AS	JP 11-16286	01/22/99	JAPAN	X	
<i>W</i>	AT	JP 7-153238	06/16/95	JAPAN		X
<i>W</i>	AU	JP 9-265733	10/07/97	JAPAN		X
<i>W</i>	AV	JP 11-215466	08/06/99	JAPAN		X
<i>W</i>	AW	JP 11-232837	08/27/99	JAPAN		X
<i>W</i>	AX	JP 11-39800	02/12/99	JAPAN		X
<i>W</i>	AY	JP 8-339637	12/24/96	JAPAN		X
<i>W</i>	AZ	WO 98/14938	04/09/98	WIPO (with English Abstract)		
<i>W</i>	AAA	WO 97/07504	02/27/97	WIPO (with English Abstract)		X
<i>W</i>	AAB	WO 97/13365	04/10/97	WIPO (with English Abstract)		X
<i>W</i>	AAC	WO 95/16262	06/15/95	WIPO (with English Abstract)		X
<i>W</i>	AAD	WO 95/12197	05/04/95	WIPO (with English Abstract)		X

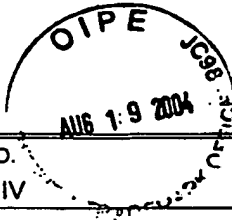
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>W</i>	AAE	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-282021 (with English translation)
<i>W</i>	AAF	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-260106 (with English translation)
<i>W</i>	AAG	Japanese Office Action (Notification of Reasons for Rejection) re: Patent Application JP 9-358546, mailing date: July 30, 2002, mailing no. 250729 (with English translation)

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

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					YES	NO
<i>AO</i>	AO	6-96559	04/08/1994	JAPAN		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered 9/12/05

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